

FOR IMMEDIATE RELEASE

BERTScope™ S offers Compliance Contour for XFP, OIF-CEI, and PCI Express

SyntheSys Research announces BERTScope S with integrated stressed eye generation

June 13, 2005 — Menlo Park, CA — The latest, more rigorous compliance testing standards for computer, storage, enterprise and telecommunications markets require new test and measurement capability up to 10 Gbps. The BERTScope S addresses test needs for higher speed (in excess of 1 Gbps) electrical components, serial links, and interfaces for computer memory, busses and back planes, including the FB-DIMM, Serial ATA, and PCI Express II standards. BERTScope S also addresses test needs for electrical and optical storage, enterprise and telecommunications components, transceivers and network equipment, including OIF-CEI and the new 4X Fiber Channel and 10G Ethernet standards.

The new BERTScope S is the first instrument with Compliance Contour, using built-in masks for fast and easy compliance tests, as specified by XFP/XFI and OIF-CEI for BER contours of 10^{-12} . "We are working closely with our customers to bring critical test functionality to market, even before these new standards are fully ratified. BERTScope S gives our customers the competitive edge they need to test their devices and network equipment with confidence in minutes, rather than hours or days using older approaches to test," said Lutz Henckels, CEO of SyntheSys Research.

BERTScope S also includes several previously optional features as standard in this new product release; including stressed eye generation, physical layer testing with jitter peak and Q-factor analysis, 2-D error mapping, and error correction emulation.

BERTScope 12500A is the flagship product and a new instrument class, combining the pattern generation and error detection of a bit error tester (BERT) with the essential eye diagram of a sampling oscilloscope. It is the *only* instrument to bridge the information gap by directly correlating bit errors to the eye diagram. Henckels added, "The visual feedback of BERTScope Compliance Contour gives our customers a fast way to not only measure the impact of jitter in their device under test, but also see the performance limits of their device."

Availability

BERTScope S is available for ordering immediately through SyntheSys Research. Please visit the SyntheSys Research website at www.stressedeye.com for more information about optical stressed eye receiver testing.

About BERTScope™

BERTScope™ is a trademark of SyntheSys Research, Inc., an innovator in high-speed signal integrity test and measurement solutions. SyntheSys Research serves the telecommunications, enterprise, storage and computer markets, with distributors worldwide. Founded in 1989, SyntheSys is a privately held corporation, headquartered in California, with the mission to deliver innovative test solutions to customers developing the next generation of high-speed serial data communications. SyntheSys' patented BitAnalyzer® error location analysis™ provides detailed information including pattern-dependent error histograms, enabling engineers to discover the source of errors. For further information, call (650) 364-1853 or visit our website at www.BERTScope.com.

Press Contact: Brett Komanovsky, brettk@bertscope.com

Marketing Communications
SyntheSys Research, Inc.
Voice: (650) 364-1853 x125
Fax: (650) 364-5716

BERTScope™ and Error Location Analysis™ are trademarks of SyntheSys Research, Inc.
BitAnalyzer® is a registered trademark of SyntheSys Research, Inc.

#

#

#